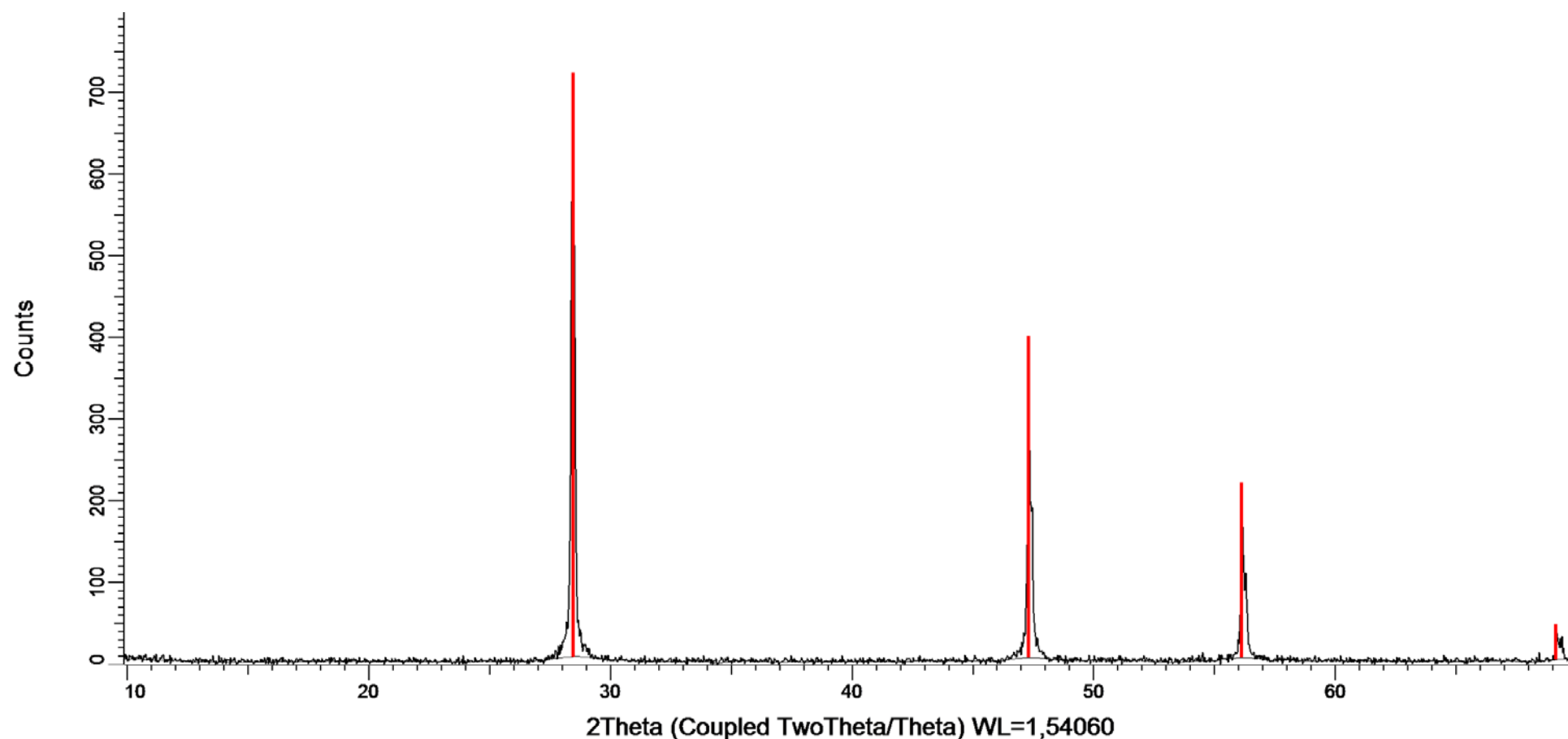


PATRÓN DE SI NIST SRM 640C 07-03-13



- 
 SI NIST XRK900 07-03-13. Barrido tipo Θ - Θ . Rango: 10 a 70 $^{\circ}2\Theta$. Paso: 0,03. Tiempo por paso: 1 seg. Cámara: XRK900. Detector: VANTEC.
- 
 Patrón de SI NIST 640c. Cúbico – a 5.43088 - b 5.43088 - c 5.43088 - α 90.000 - β 90.000 - γ 90.000 – Centrado en las caras – Fd-3m (227) – Z 8 – V 160.181

07 de marzo de 2013



INFORME DE CALIBRACIÓN XRK900

Si NIST 640c D8C 07-03-13

Range Number : 1

R-Values

Rexp : 27.66 Rwp : 33.41 Rp : 22.98 GOF : 1.21
 Rexp` : 6.16    Rwp` : 7.44 Rp` : 7.38 DW : 1.62

Instrument

Primary radius (mm) 200.5
 Secondary radius (mm) 200.5
 Linear PSD 2Th angular range (°) 3
 FDS angle (°) 0.6
 Beam spill, sample length (mm) 14
 Intensity not corrected
 Full Axial Convolution
 Filament length (mm) 12
 Sample length (mm) 14
 Receiving Slit length (mm) 12
 Primary Sollers (°) 2.5
 Secondary Sollers (°) 4

hkl Phase - 1 Le Bail method

Phase name	Silicio
R-Bragg	2.348
Spacegroup	227
Cell Mass	0.000
Cell Volume (Å³)	159.997(49)
Wt% - Rietveld	0.000
Crystallite Size	
Cry size Lorentzian (nm)	143(22)
k: 1 LVol-IB (nm)	91(14)
k: 0.89 LVol-FWHM (nm)	127(20)
Strain	
Strain L	0.066(31)
e0	0.0166(77)
Lattice parameters	NIST 640c Certificate
a (Å)	5.42881(56) 5.43311946(92)

h	k	l	m	d	Th2	I	=
1	1	1	8	3.13432	28.45377	5.2	
0	2	2	12	1.91937	47.32245	8.27	
3	1	1	24	1.63685	56.14635	7.2	
2	2	2	8	1.56716	58.88166	0.123	
0	0	4	6	1.35720	69.16100	2.99	

